IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

MARAKHTANOV et al

Serial No.: 10/808,795

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Title: PLASMA PROCESSING SYSTEM

CONTROL

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Group Art Unit: 2821-2828 Examiner: UNASSIGEND Docket: P1220/LMRX-P030

Confirmation No.: 6020

INFORMATION DISCLOSURE STATEMENT

US PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant	Reference to Related Case
D/		US-5933314	1999-08-03	Lambson et al.	

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	Examiner Initials	Cite No.	Document Number	Publication Date	Applicant	Reference to Related Case	T	
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Examiner Signature Dovi	Date Considered	6/12/05
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